**Preliminary Amendment** 

Applicant: Javier Argüelles Serial No.: 10/717,214

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Docket No.: I435.105.101

Title: PROCESS AND DEVICE FOR TESTING A SERIALIZER CIRCUIT ARRANGEMENT AND PROCESS

AND DEVICE FOR TESTING A DESERIALIZER CIRCUIT ARRANGEMENT

## **IN THE ABSTRACT**

Please amend the Abstract as follows:

## PROCESS AND DEVICE FOR TESTING A SERIALIZER CIRCUIT ARRANGEMENT AND PROCESS AND DEVICE FOR TESTING A DESERIALIZER CIRCUIT ARRANGEMENT

## **ABSTRACTAbstract**

A process and a device are proposed for testing a serializer and deserializer circuit arrangement (2, 3), where to control the test sequence a simple digital interface (12)-is used. To test the serializer circuit arrangement (2)-firstly the quality of a multiphase clock signal (CLK) of the serializer circuit arrangement (2)-and secondly the ability to transmit a preset bit pattern are tested. To test the deserializer circuit arrangement (3)-the quality of the multiphase clock signal (CLK) and the quality of a data eye obtained during clock and data recovery are tested together with the quality of the clock recovery.